

PROBE STATION THERMAL CHUCK WITH SHIELDING FOR
CAPACITIVE CURRENT

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ABSTRACT OF THE DISCLOSURE

To reduce noise in measurements obtained by probing a device supported on surface of a thermal chuck in a probe station, a conductive member is arranged to intercept current coupling the thermal unit of the chuck to the surface supporting
10 the device. The conductive member is capacitively coupled to the thermal unit but free of direct electrical connection thereto.